

INTERNATIONAL SEARCH REPORT

PCT/IB2004/002444

A. CLASSIFICATION OF SUBJECT MATTER

IPC 7 G03F7/20

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC 7 G03F H01L

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, COMPENDEX, INSPEC, WPI Data, IBM-TDB

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	US 2003/068565 A1 (KI WON-TAI ET AL) 10 April 2003 (2003-04-10)	10, 11
A	abstract figures 2-4, 6	1, 12
A	US 5 902 703 A (LEROUX ET AL) 11 May 1999 (1999-05-11) cited in the application abstract figure 8	1, 10-12
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☒ Further documents are listed in the continuation of box C.☒ Patent family members are listed in annex.

* Special categories of cited documents:

- *A* document defining the general state of the art which is not considered to be of particular relevance
- *E* earlier document but published on or after the international filing date
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- *O* document referring to an oral disclosure, use, exhibition or other means
- *P* document published prior to the international filing date but later than the priority date claimed

- *T* later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention
- *X* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone
- *Y* document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.
- *&* document member of the same patent family

Date of the actual completion of the international search

27 May 2005

Date of mailing of the international search report

09/06/2005

Name and mailing address of the ISA

European Patent Office, P.B. 5818 Patentlaan 2
NL - 2280 HV Rijswijk
Tel. (+31-70) 340-2040, Tx. 31 651 epo nl,
Fax: (+31-70) 340-3016

Authorized officer

Menck, A

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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT		
Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	BOUROV A ET AL: "Impact of flare on CD variation for 248nm and 193nm lithography systems" PROCEEDINGS OF THE SPIE, SPIE, BELLINGHAM, VA, US, vol. 4346, September 2001 (2001-09), pages 1388-1393, XP002322054 ISSN: 0277-786X the whole document -----	1,10-12
A	KIM JAE-HWAN AT AL: "Wavefront aberration measurement in 157-nm high numerical aperture lens" PROCEEDINGS OF THE SPIE, vol. 5040, no. III, July 2003 (2003-07), pages 1408-1419, XP002329622 the whole document -----	1,10-12
A	DONGSEOK NAM ET AL.: "Effectiveness and confirmation of local area flare measurement method in various pattern layouts" PROCEEDINGS OF THE SPIE, vol. 4691, August 2002 (2002-08), pages 57-66, XP002329623 the whole document -----	1,10-12

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Patent document cited in search report		Publication date	Patent family member(s)		Publication date
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			KR	2003014098 A	15-02-2003
			US	2005083518 A1	21-04-2005
US 5902703	A	11-05-1999	US	6301008 B1	09-10-2001
			US	5962173 A	05-10-1999